

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination GAUTHIER ET AL.	
		10/075,757	Examiner Hugh Jones	
		Art Unit 2128	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,819,192	11-2004	Gauthier et al.	331/74
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Heydari et al.; Analysis of jitter due to power-supply noise in phase locked loops; IEEE 2000 Custom Int. Ckt. Conf.; pp. 443-446; 5/2000.
	V	Egan et al.; Characterization and verification of phase-locked loops; IEEE Instrumentation and Measurement Technology Conf.; pp. 1697-1702; 5/2001.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.